

Software: Testing, Commissioning, and Operation

Oxford SVT working meeting

16 Dec. 2025

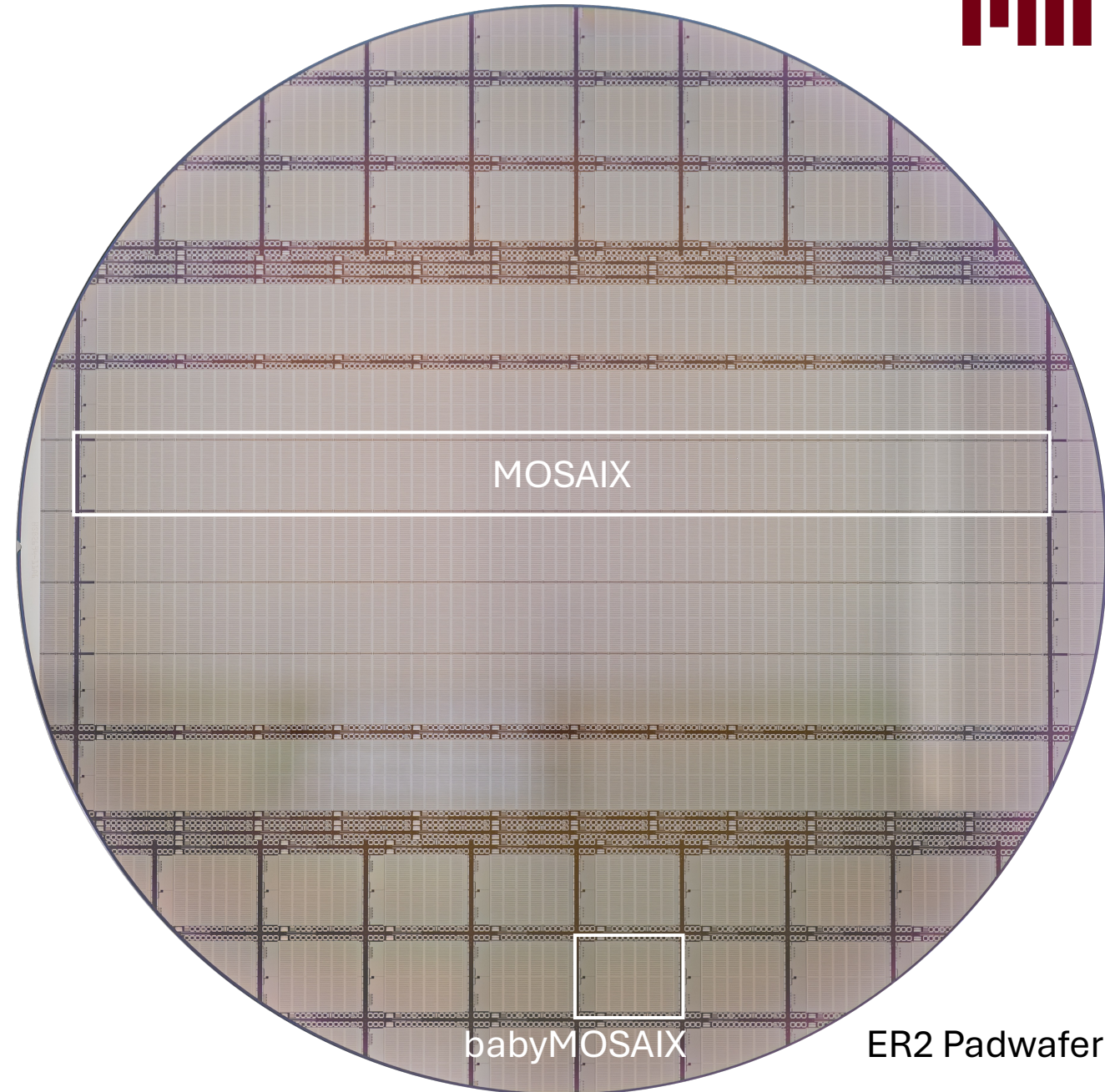
Gregor Eberwein (MIT) on behalf of SVT WP2

Outline

- MOSAIX recap
- Testing infrastructure, qualification and status
- SVT SW framework

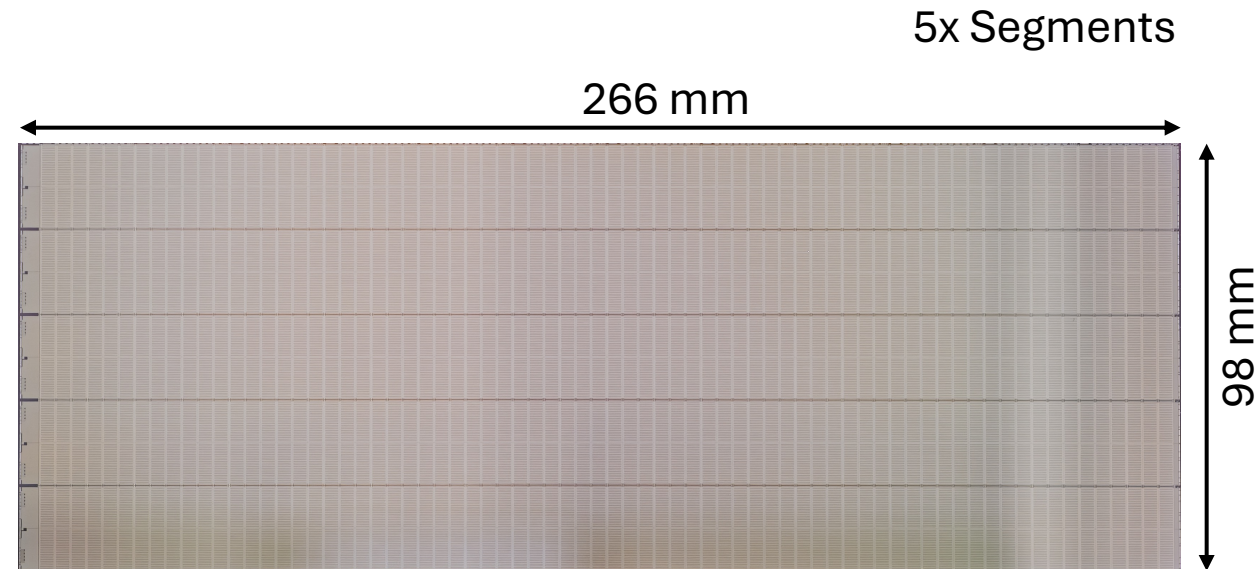
MOSAIX chip status

- MOSAIX wafers (ER2) arriving in February
Pad wafers: **arrived December**
- ER3 submission preparation in progress -> feedback to designers by mid 2026



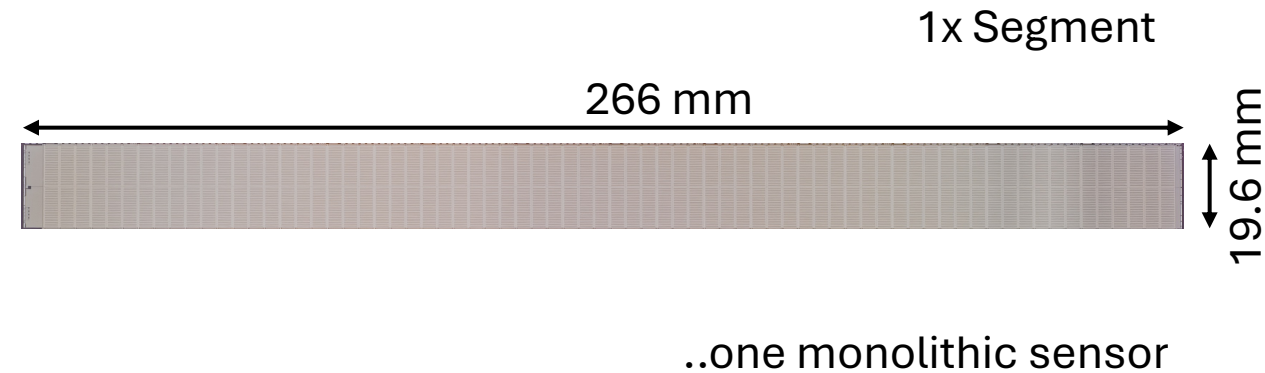
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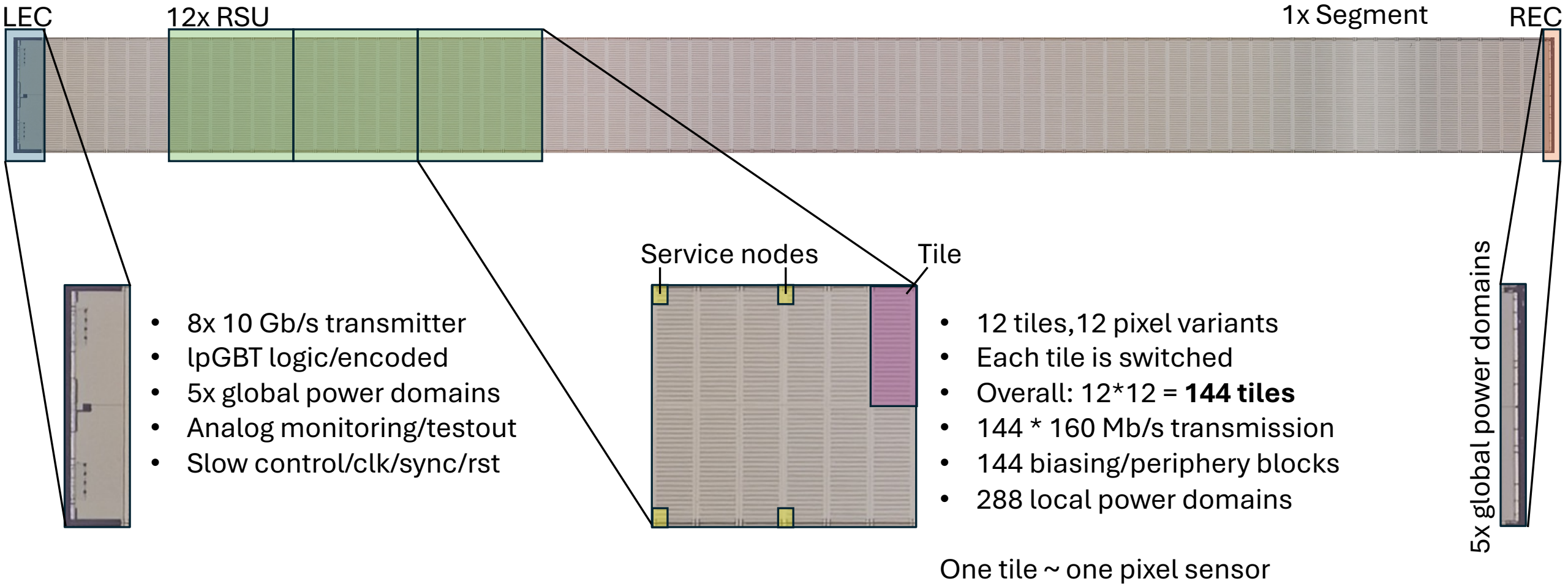


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MOSAIX anatomy



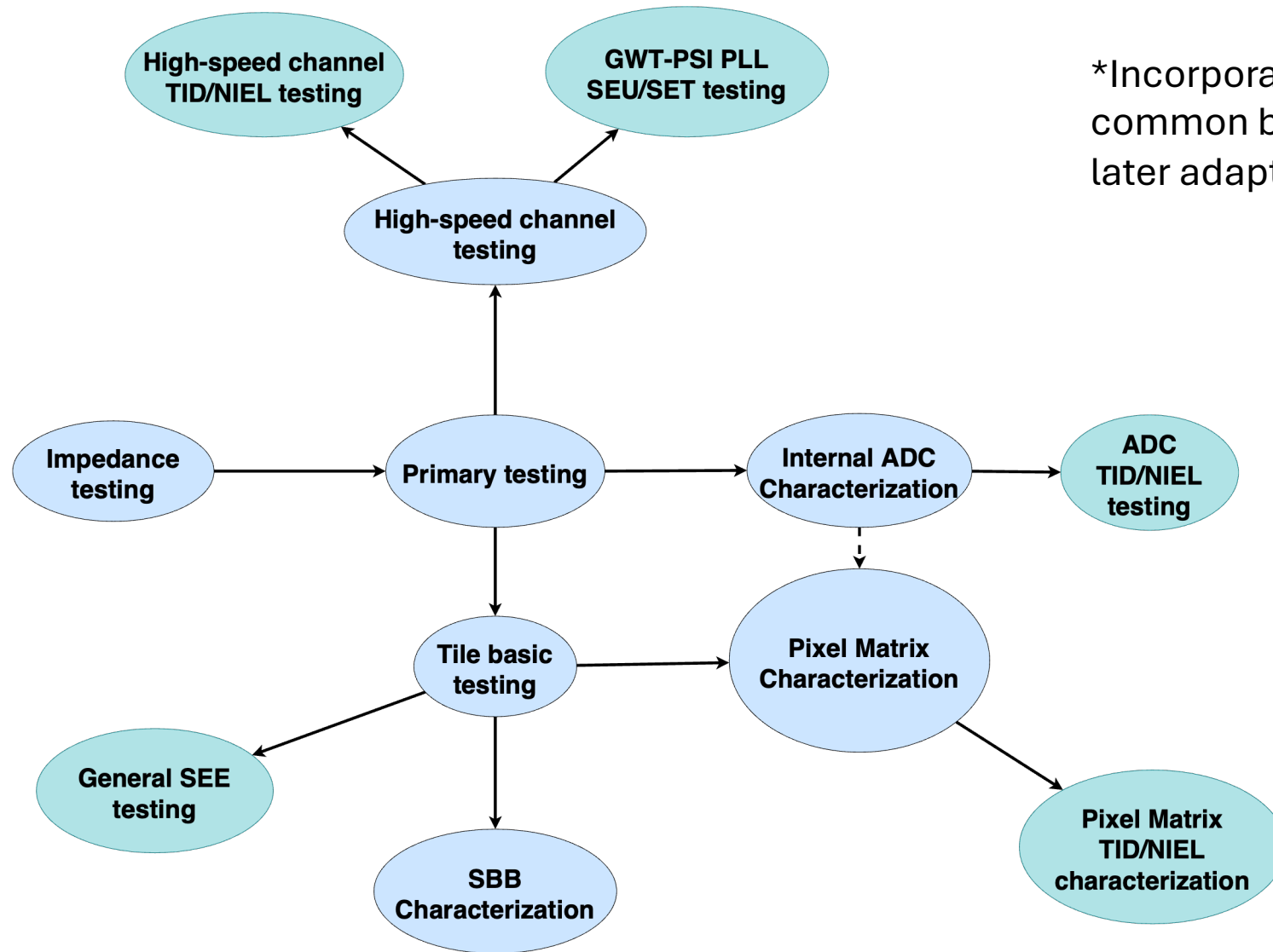
MOSAIX qualification goals

- Verify functionality of all features
- Yield of blocks
- Identify the pixel variant
- 10 Gb/s transmission on-wafer
- Radiation effects
- *ambition for day one readiness*

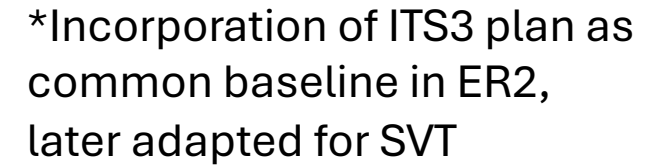
Test stage	Dependencies	Description
Primary testing	Impedance testing	Testing of services and global supplies, slow control access and critical features, e.g., service node control. Pre-requisite for all further testing.
Impedance testing	Primary testing	TBD
Tile basic testing	Primary testing	Testing tile-level functionality. SBB data transfer.
Analog circuitry and ADC testing	Primary testing	Characterization of on-chip ADC and analog monitoring network. Includes also testing of bandgap reference.
Pixel matrix characterization	Tile basic testing /ADC testing?	Characterization of pixel matrix.
High-speed channel	Primary testing	Testing high-speed channel
SBB characterization	Tile basic testing	Full characterization of the SBB. Check margins for data transfer.
General SEE testing	Tile basic testing	SEU cross-section, SEL susceptibility
Pixel matrix TID/NIEL characterization	Pixel matrix characterization	Pixel matrix performance after radiation
High-speed channel TID/NIEL testing	High-speed channel	LEC/serializer performance after radiation
ADC TID/NIEL testing	ADC testing	ADC performance after radiation
GWT-PSI PLL SEU/SET testing	High-speed channel	Check PLL susceptibility for SEU/SET

*ITS3 stage plan

Qualification and characterisation stages



*Incorporation of ITS3 plan as common baseline in ER2, later adapted for SVT



Tests *before* powering on the individual tiles

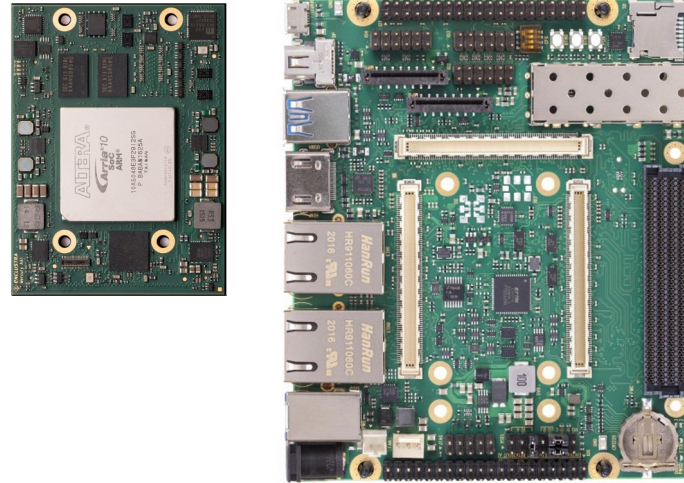
Testing Infrastructure

2x power supply



SMU & multiplexer
for impedance

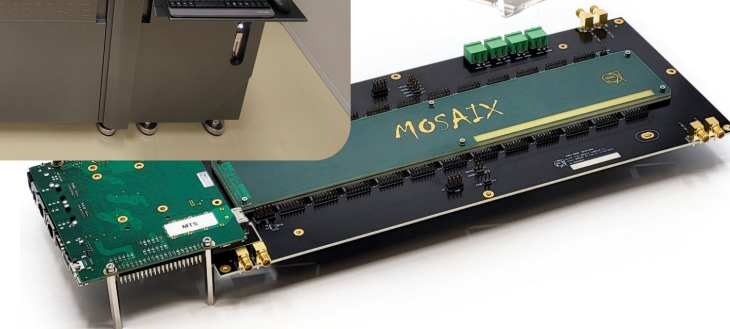
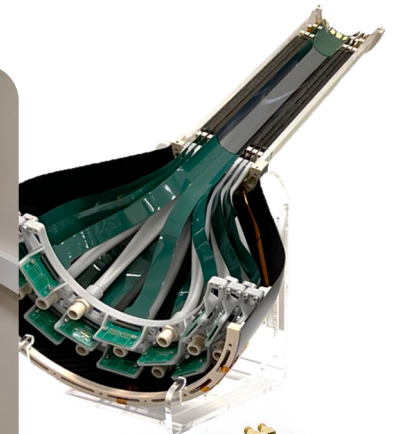
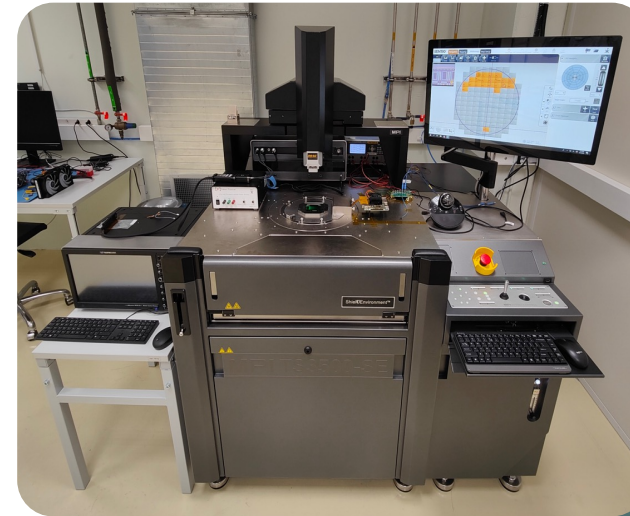
Altera Arria 10 & Enclustra baseboard



1 set/MOSAIX (Segment)
Connected via USB3 <-> PC

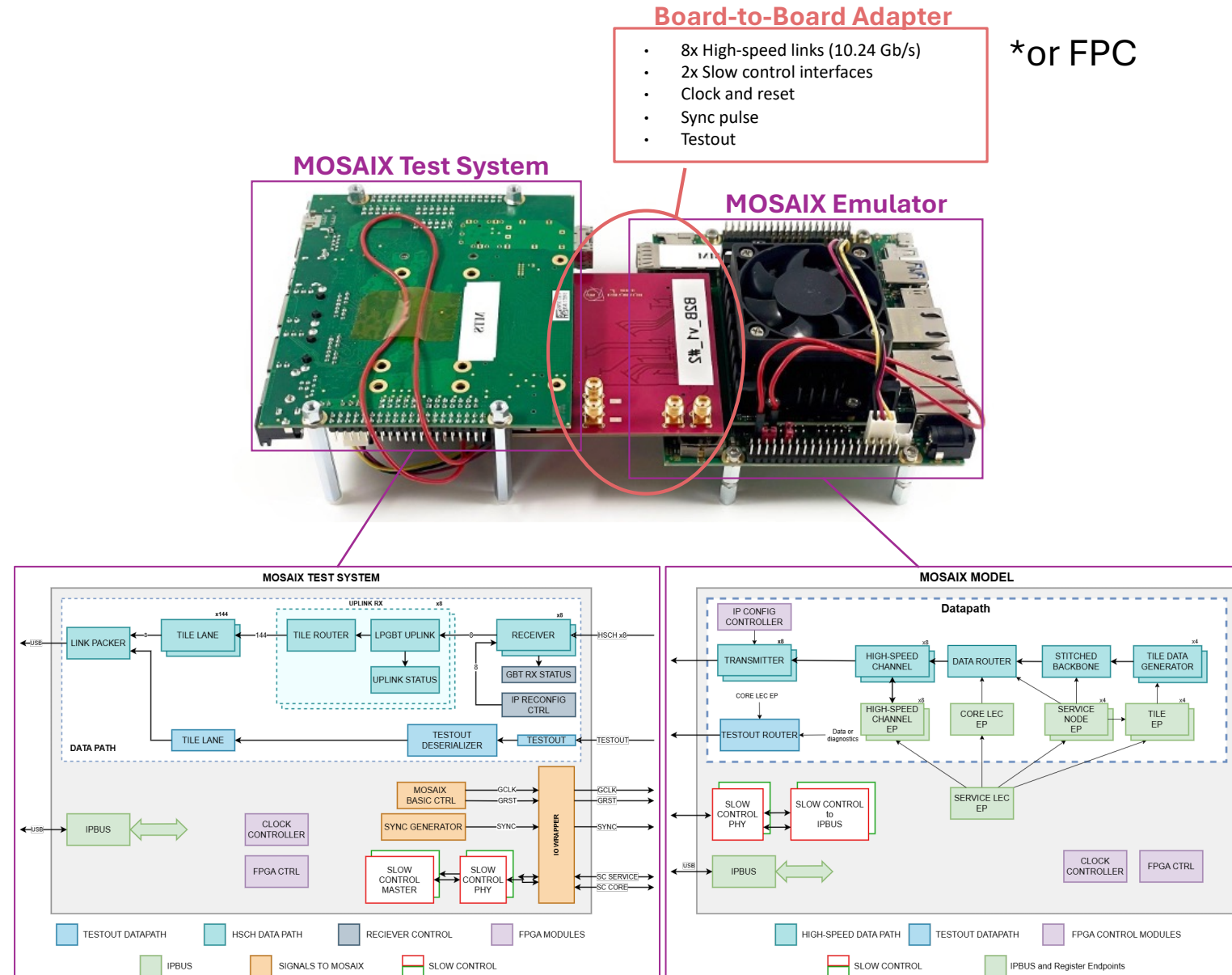
MOSAIX targets:

- **Wafer Probing** see *Stefano's presentation*
- Carrier PCB
- Bent models/test beams



Tests and readiness

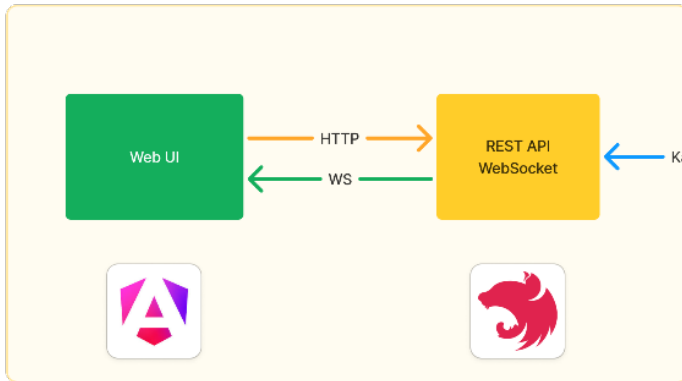
- Firmware -> done (ITS3)
 - Includes emulator allows to test framework
- Hardware agnostic API -> ongoing (ownership of small part)
- List of tests & status thereof
 - Readiness report this week
 - It will be possible to run set of tests when chips are available



SVT SW framework

Web based UI
Produces commands
& visualizes data

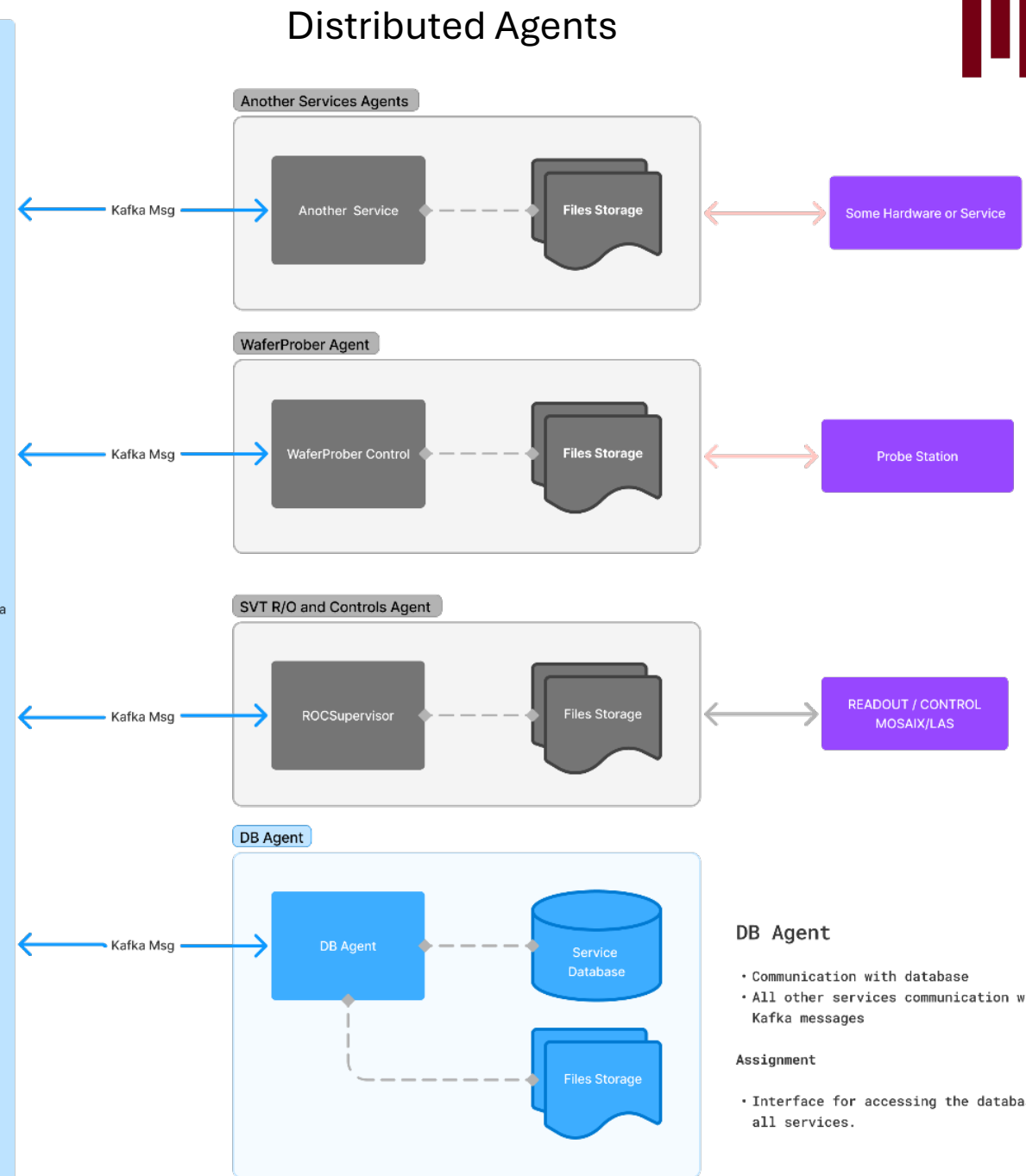
UI



UI

- Web based service, consist of 2 parts:
 - Front-end
 - running in the browser
 - Back-end
 - ensure communication between other services, provides HTTP, WS, Kafka interfaces for communication
- Assignment
 - UI for start/stop operations
 - UI for data overview/analysis

Distributed Kafka
backbone



DB Agent

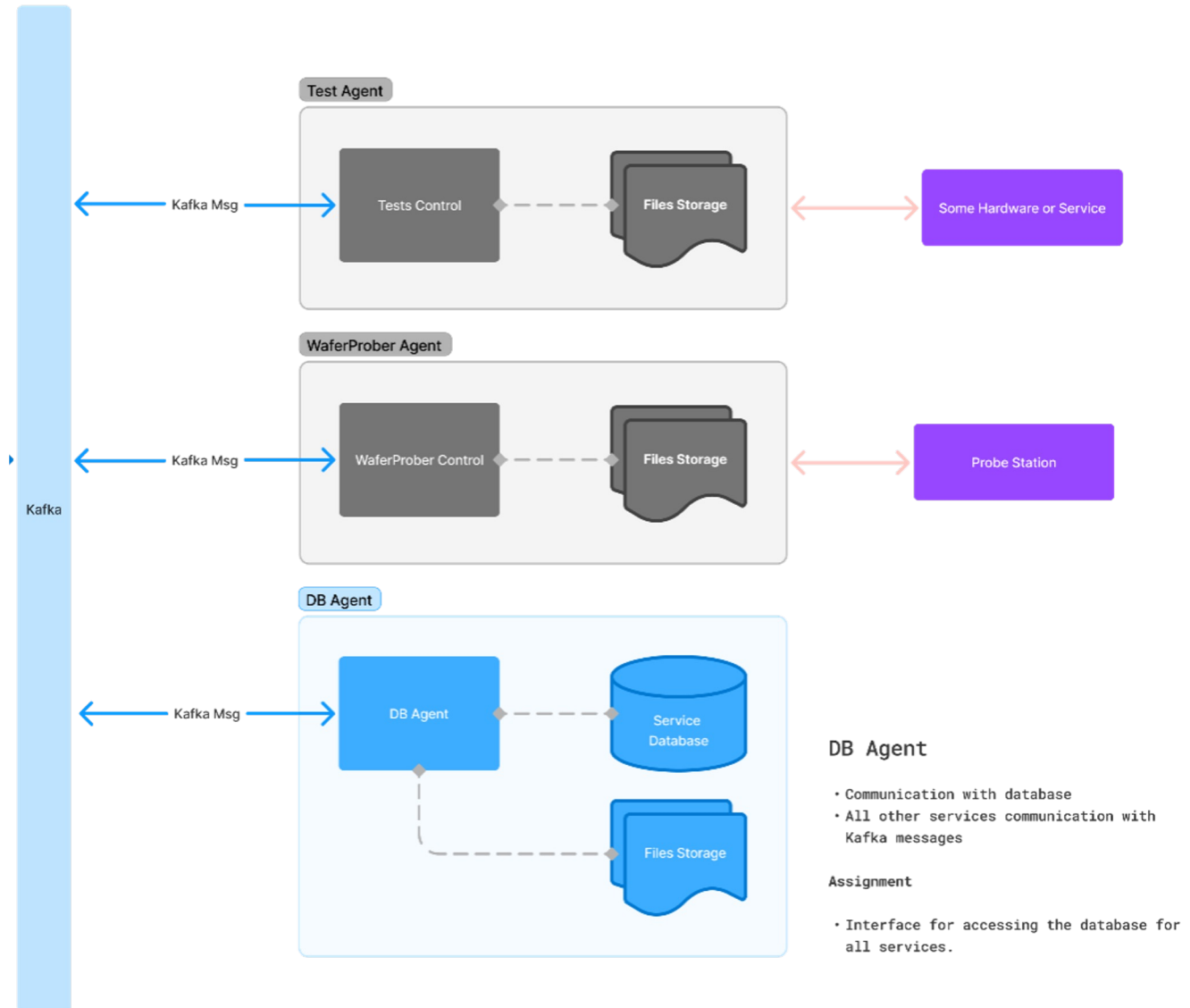
- Communication with database
- All other services communication with Kafka messages

Assignment

- Interface for accessing the database for all services.

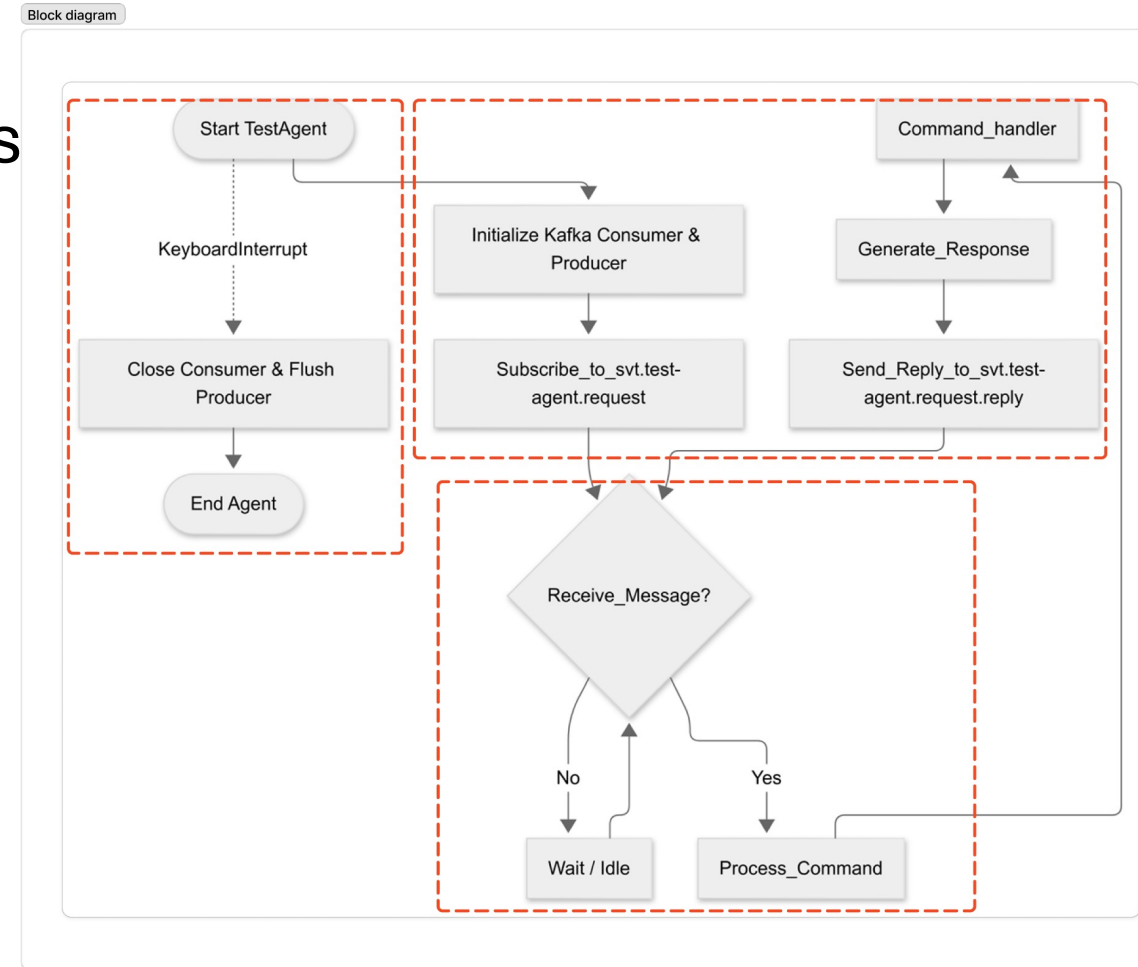
Agents under development

- Test Agent
 - Runs the chip tests
- Wafer Probe Agent
 - Controller to operate the wafer prober
- Database Agent
 - Communication with DB (CERN DB on demand service)



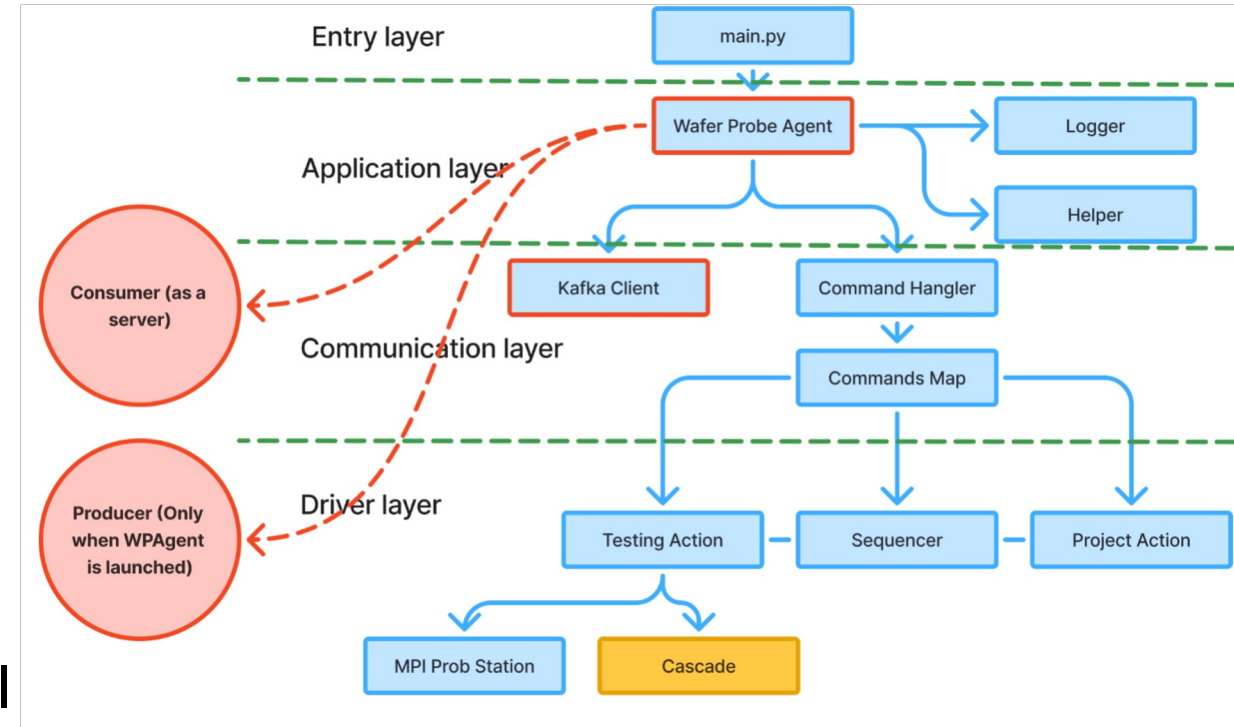
Test Agent

- Individual agents for separate SVT ASICs
- For MOSAIX:
 - Full integration of ITS3 ER2 qualification and characterisation tests in SVT SW framework
 - Derive qualification strategy for ER3
 - Use emulator setup (running) to create dummy tests
- Status: ongoing
 - New: test sequencer, direct DB Agent access, direct feedback to UI



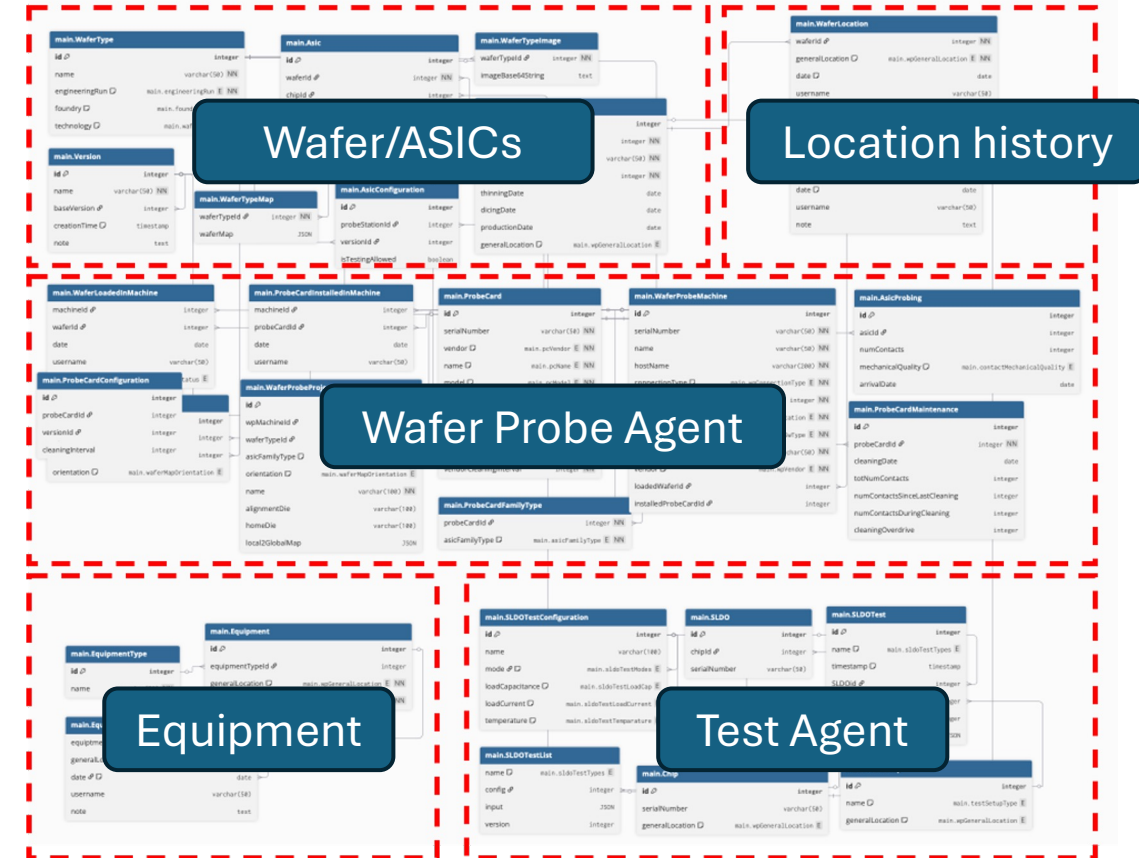
Wafer Probe Agent

- Central controller to operate wafer probe stations autonomously
- Interface with the remaining testing framework
 - I.e. move to chip, perform test (sequence)
- Status: ongoing
 - New: set of interace commands for MPI wafer prober, retrieving DB info, command sequences(json), wafer maps -> see *Stefano's presentation*



DB Agent

- DB Agent is the main communication layer with the Database
 - Kafka consumer/producer for pull and push request/reply messages
- DB structure: work in progress →
 - New: history tracking
- Database on temporary dev instance



User interface (UI)

- Global interface between operator, DB, and all Agents
- Status: ongoing
 - New: chip tracking, creation of new ASICs individually or in bulk

The screenshot displays the EPIC (Electronic Production Information Control) user interface. The main view is for 'Asics' under 'asic-1'. The sidebar on the left contains navigation icons for WPM, ASICs, Wafer Map, Admin, and DEV. The main content area shows details for 'asic-1' and a 'Voltage Scan' section. A red box highlights a menu with 'Location History' and 'Update Location' options. An arrow points from 'Location History' to a 'Chip Location History' modal window. Another arrow points from 'Update Location' to an 'Update Chip Location' modal window.

Chip Location History

Location	Changed At	Note	Updated By
CERN_186_R_E10	2025-10-31	Some reason	
Prague	2025-10-21	Some reason ...	

Update Chip Location

New Location*
Prague

Location Change Date
2025-10-21

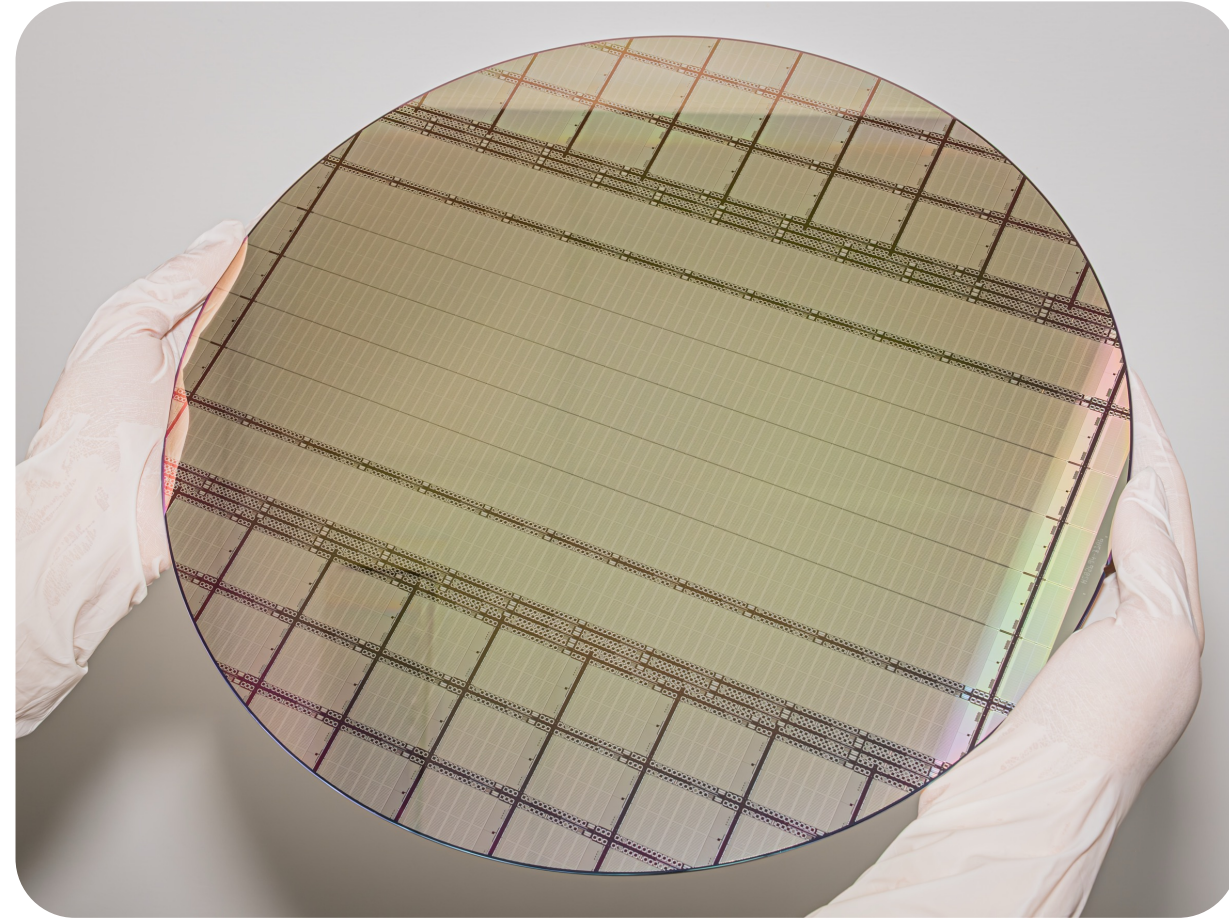
Date Format: 2025-01-31

Note*
Some reason ...

Cancel Update

Conclusions

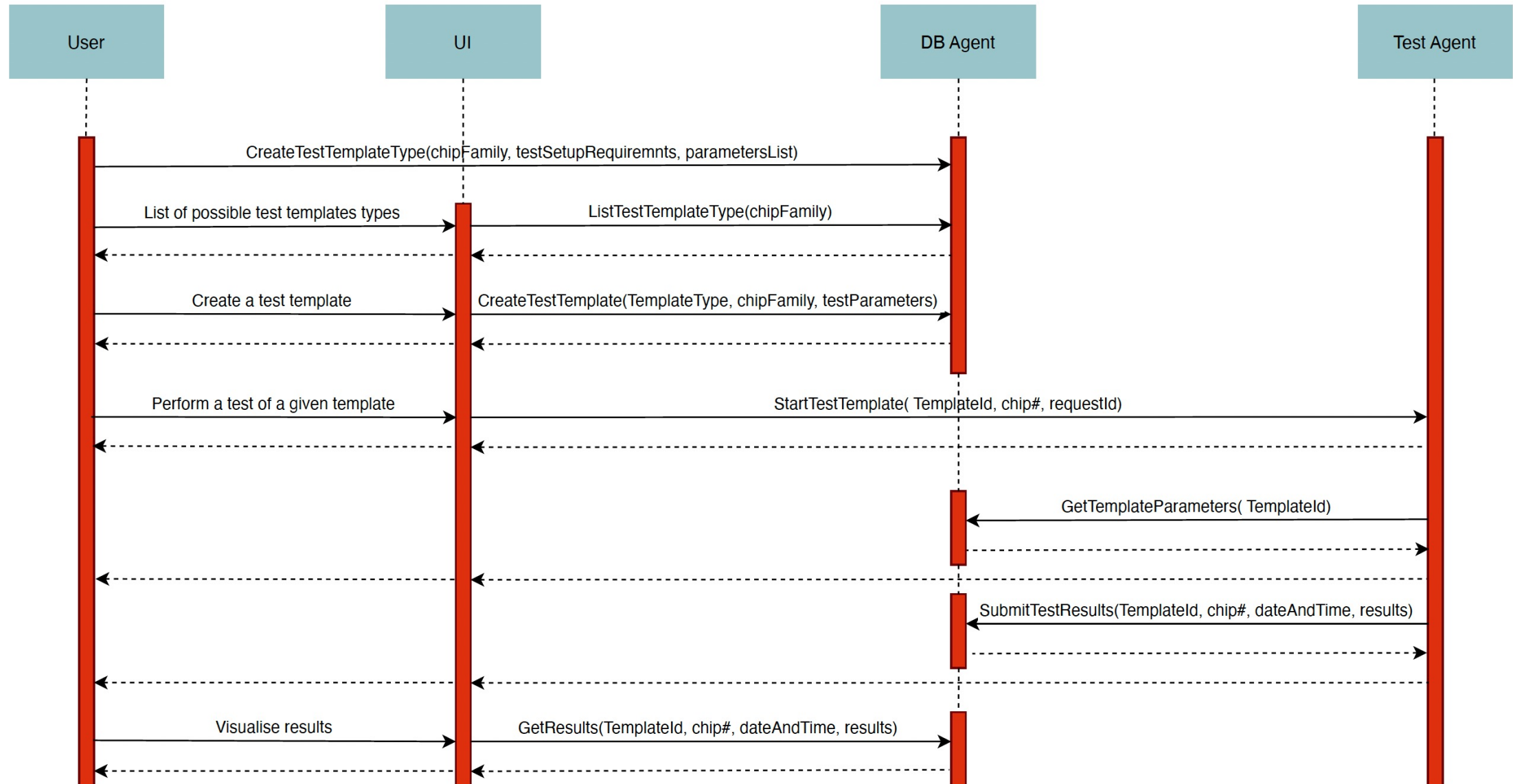
- MOSAIX wafers arrive early 2026
- Foundational infrastructure ready and tested, using emulator for pre-testing
- MOSAIX test sequence development in progress
- SVT SW framework is steadily growing, Agents need still work. Next: use emulator to run realistic test cases
 - Input and contributions very welcome
 - Agnostic and flexible in regard to adding Agents and functionality for testing sites and production
 - Goal of plug-and-play with tested hardware

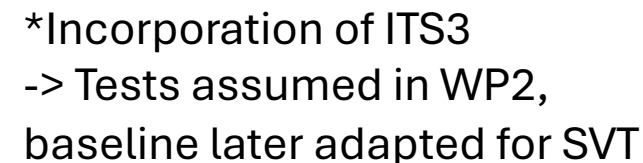


BACKUP



Example communication



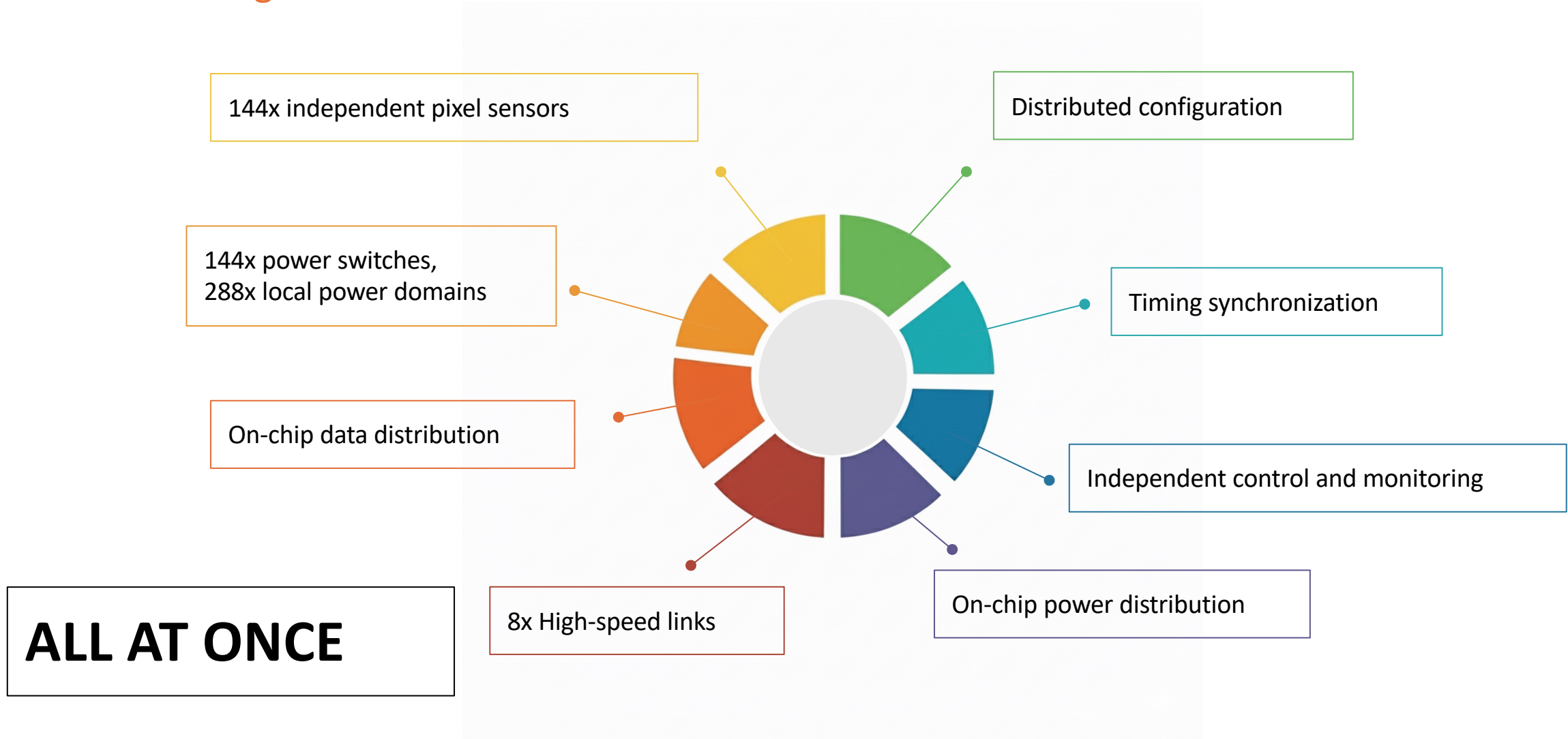


Tests *before* powering on the individual tiles

Test Block	Test sequence	Sub sequence	Report
Power on single W@B at a time - L@VDD0	L@VDD on, close switch S1 Allow Test L@VDD off, open switch	SC CORE Above Test, Tie EP	GVDD0 - 1.2V, 1.2V, 1.2V
Sleep power all files, extract information on how many files are alive			
Slow Control CORE - checking for alive files, single file at a time	L@VDD on, close switch SC CORE Read/Write Test SC CORE Stress Test L@VDD off, open switch	SC CORE Read/Write Test, LEE Core EP SC CORE Read/Write Test, LEE HPA1 EP SC CORE Read/Write Test, Tie EP SC CORE Stress Test, LEE Core EP SC CORE Stress Test, LEE HPA1 EP SC CORE Stress Test, Tie EP	GVDD0 - 1.2V, 1.2V, 1.2V
Power on all files - L@VDD0	Power on all files, left to right SC Allow Test	SC CORE Allow Test, Tie EP and VEE	GVDD0 - 1.2V, 1.2V (WARNING, difference is correct)
Slow Control CORE - checking for alive files	Power on all files, left to right SC CORE Read/Write Test SC Breakout Test SC CORE Stress Test Power off all files, right to left	SC CORE Read/Write Test, LEE Core EP SC CORE Read/Write Test, LEE HPA1 EP SC CORE Read/Write Test, Tie EP SC Breakout Test SC CORE Stress Test, LEE Core EP SC CORE Stress Test, LEE HPA1 EP SC CORE Stress Test, Tie EP	GVDD0 - 1.2V, 1.2V (WARNING, difference is correct)
S@B Testing	Test single S@B buffer Test step up to go to S@B DATA TRANSFER READY Test no step up going to go S@B DATA TRANSFER READY Measure clock jitter on REC		GVDD0 - 1.2V, 1.2V, 1.2V
Power on all files with S@B DATA TRANSFER READY	Power on all files, left to right S- Allow Test Power off all files, right to left	SC CORE Allow Test, Tie EP and VEE	GVDD0 - 1.2V, 1.2V (WARNING, difference is correct)
Go Data Transmission Test per W@B	Test no step up going to go S@B DATA TRANSFER READY L@VDD on, close switch Tie@B P@B Test Tie@B Test Patterns Test (TPGA) Preceder S@B parameter case L@VDD off, open switch		GVDD0 - 1.2V, 1.2V, 1.2V
S@B Data Integrity Test	Power on all files, left to right Tie@B P@B Test Preceder S@B parameter case Power off all files, right to left		GVDD0 - 1.2V, 1.2V (WARNING, difference is correct)
Logic digital capture	L@VDD on, close switch Lock Packet Test Length Data Packet Test Plant Matrix Read Test Plant Matrix Digital Pulse Test Plant Matrix Digital Pulse Test with clock gating L@VDD off, open switch	Empty Data Packet Test, Go Mode, Sequence Empty Data Packet Test, Go Mode, Control seq Empty Data Packet Test, Wake up from sleep, all attributes, Sequence Empty Data Packet Test, Mask all pins, Sequence Empty Data Packet Test, Mask all pins, Sequence Plant Matrix Mask Test Plant Matrix Mask Test Plant Digital Pulse Test, 40 Mbit Plant Digital Pulse Test, 20 Mbit	GVDD0 - 1.2V, 1.2V (WARNING, difference is correct)
Manual digital activation	Power on all files, left to right Data Readback Test Power off all files, right to left	Data Readback Test, Functional Data Readback Test, Stress	GVDD0 - 1.2V, 1.2V (WARNING, difference is correct)
Logic sequence features test	L@VDD on, close switch Lower Memory Integrity Test Transcode Max Counter Test L@VDD off, open switch		

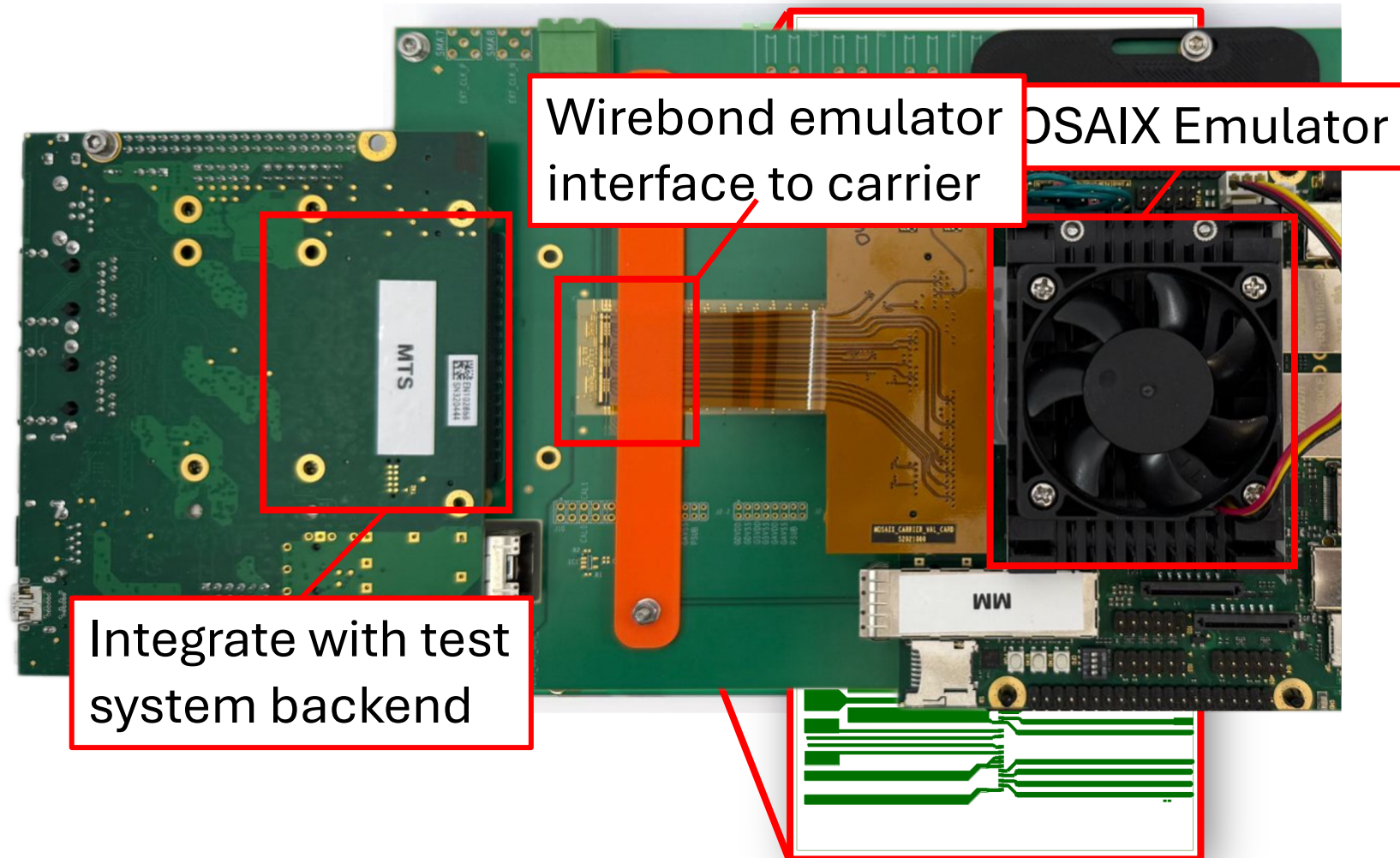
Qualification of MOSAIX

The Challenge_(s)



Qualification Infrastructure

Pre-Silicon Verification



Wafer probing @ CERN DSF

Status

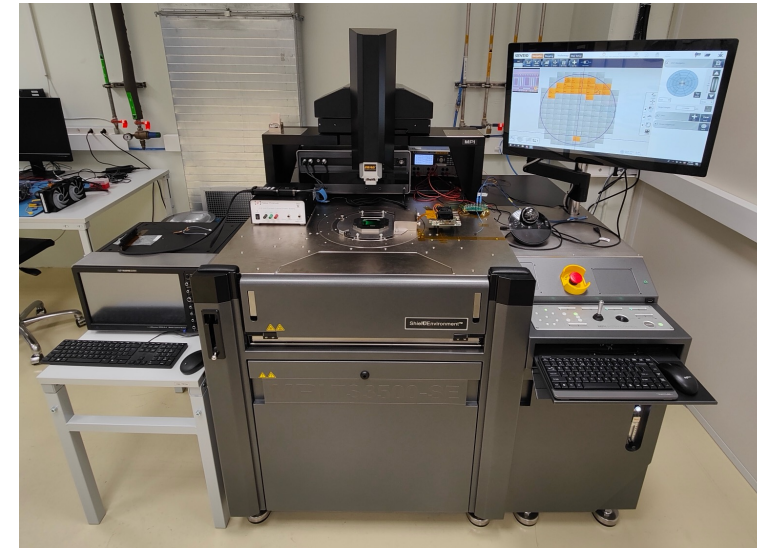
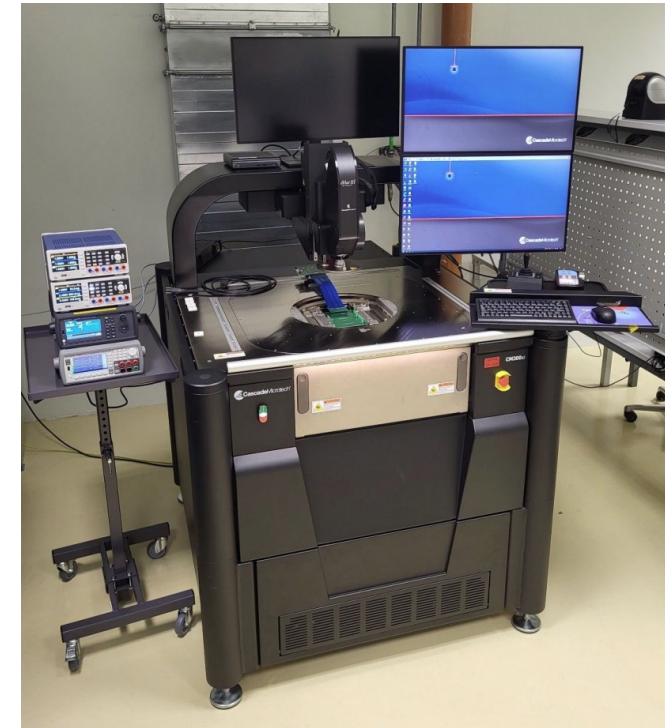
- Two probe setups
- Both probers are fitted for:
 - impedance measurements
 - power ramping
 - functional testing
- All equipment acquired and at CERN
- Contact and automation testing with pad wafers: **ONGOING**

CERN prober – Standard cantilever needle probing

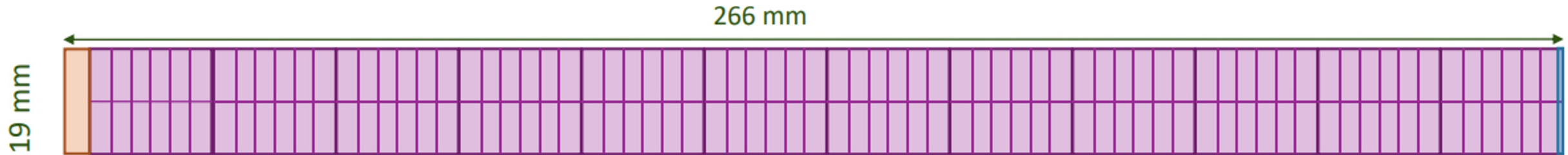
- Probe card: 1x **DELIVERED**, 2x **ARRIVING SOON**
- Functional tests with emulator: **ONGOING**

MIT prober – High-speed vertical needle probing (R&D)

- Studies on high-speed probing: **DONE**
- Probe card: **ORDERED**, expected delivery EOY (single-segment) and January 2026 (multi-segment)

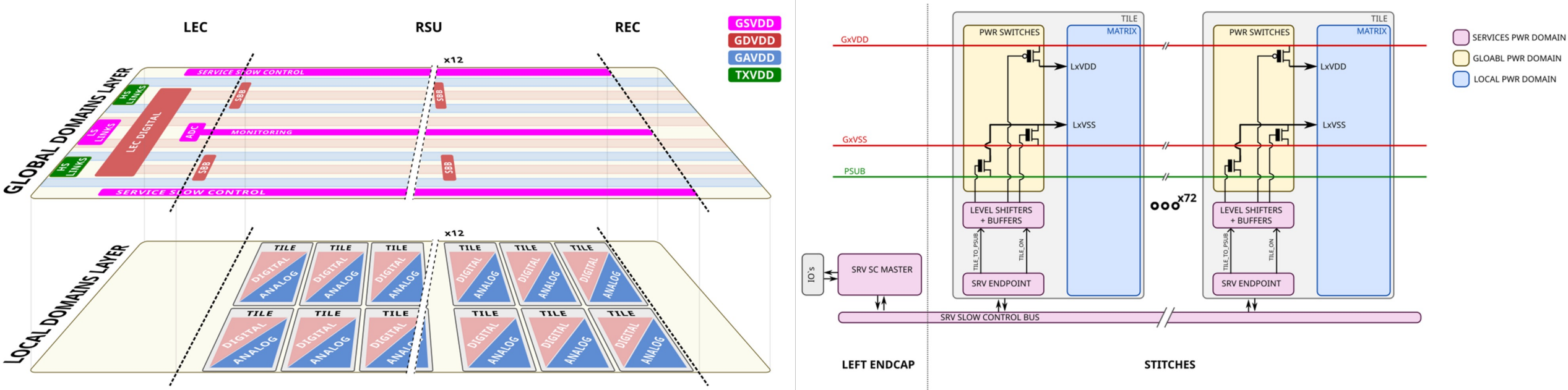


MOSAIX Core Specs



- 93% sensitive area
- 0.7% modularity
- 144 tiles
- 4.4 MHz/cm² particle rate
- 30.72 Gb/s off-chip data transmission
- minimum 2 μ s integration time
- < 40 mW/cm²
- 1013 NIEL (1 MeV neq cm⁻²)
- 10 kGray TID
- Triple modular redundancy
- 20.8 x 22.8 μ m² pixel size
- 444 x 156 pixels per tile
- Detection efficiency > 99%
- Fake-hit rate: < 0.1 pixel⁻¹s⁻¹

MOSAIX



Detector R&D

Production: ER2 & ER3

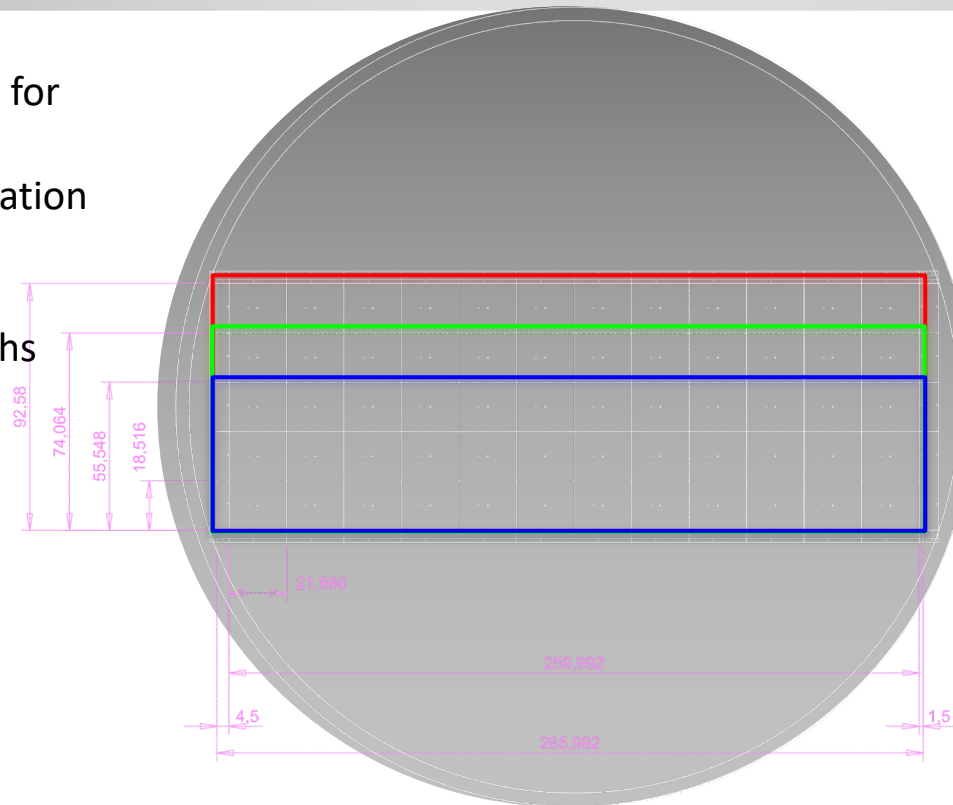
Now

Q3 2026

Engineering Run 2

- Different pixel variants for operational margins
- Design in-depth verification ongoing
- 33 wafers: 4 months
- 25 pad wafers: 3 months
- 1 month for dicing

PX1	PX2	PX3	PX4	PX5	PX6
PX7	PX8	PX9	PX10	PX11	PX12



Engineering Run 3

- Final pixel variant
- Functionally identical to ER2
- ER2 implementation procedure and scripts identical for ER3-For ER3 much shorter design and verification
- As little as 6 wafers needed

?	?	?	?	?	?
?	?	?	?	?	?

- 12 RSUs
- 4 unit slices per RSU
- 1 service node per unit slice
- 12 tiles per RSU (6 top & 6 bottom)
- 4 readout regions per tile
 - Combined into 1 tile readout link

